

**Notice of References Cited**

Application/Control No.

10/574,974

Applicant(s)/Patent Under  
Reexamination  
ORON ET AL.Examiner *QML*  
Quyen P. Leung *7/07*Art Unit  
2874

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,099,552	08-2006	Oron et al.	385/139
*	B	US-5,534,000	07-1996	Bruce, Johnny M.	606/15
*	C	US-5,530,780	06-1996	Ohsawa, Masami	385/31
*	D	US-2005/0135772	06-2005	Nield et al.	385/140
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	EP 399660 A1	11-1990	European Patent	DAIGNAULT et al.	
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	DEFINITION OF SCATTERING, WORDNET.PRINCETON.EDU/PERL/WEBWN, PRINTED 6/27/07
	V	DEFINITION OF DIFFUSION, EN.WIKIPEDIA.ORG/WIKI/DIFFUSION, PRINTED 6/27/07
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.